

INTERNATIONAL STANDARD

NORME INTERNATIONALE

BASIC EMC PUBLICATION
PUBLICATION FONDAMENTALE EN CEM

AMENDMENT 2
AMENDEMENT 2

**Electromagnetic compatibility (EMC) –
Part 4-3: Testing and measurement techniques – Radiated, radio-frequency,
electromagnetic field immunity test**

**Compatibilité électromagnétique (CEM) –
Partie 4-3: Techniques d'essai et de mesure – Essai d'immunité aux champs
électromagnétiques rayonnés aux fréquences radioélectriques**

WORLDWIDE
Sample Document
standards.iteh.ai



THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2010 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester.

If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de la CEI ou du Comité national de la CEI du pays du demandeur.

Si vous avez des questions sur le copyright de la CEI ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de la CEI de votre pays de résidence.

IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland
Email: inmail@iec.ch
Web: www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

- Catalogue of IEC publications: www.iec.ch/searchpub

The IEC on-line Catalogue enables you to search by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, withdrawn and replaced publications.

- IEC Just Published: www.iec.ch/online_news/justpub

Stay up to date on all new IEC publications. Just Published details twice a month all new publications released. Available on-line and also by email.

- Electropedia: www.electropedia.org

The world's leading online dictionary of electronic and electrical terms containing more than 20 000 terms and definitions in English and French, with equivalent terms in additional languages. Also known as the International Electrotechnical Vocabulary online.

- Customer Service Centre: www.iec.ch/webstore/custserv

If you wish to give us your feedback on this publication or need further assistance, please visit the Customer Service Centre FAQ or contact us:

Email: csc@iec.ch
Tel.: +41 22 919 02 11
Fax: +41 22 919 03 00

A propos de la CEI

La Commission Electrotechnique internationale (CEI) est la première organisation mondiale qui élabore et publie des normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

A propos des publications CEI

Le contenu technique des publications de la CEI est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

- Catalogue des publications de la CEI: www.iec.ch/searchpub/cur_fut-f.htm

Le Catalogue en-ligne de la CEI vous permet d'effectuer des recherches en utilisant différents critères (numéro de référence, texte, comité d'études,...). Il donne aussi des informations sur les projets et les publications retirées ou remplacées.

- Just Published CEI: www.iec.ch/online_news/justpub

Restez informé sur les nouvelles publications de la CEI. Just Published détaille deux fois par mois les nouvelles publications parues. Disponible en-ligne et aussi par email.

- Electropedia: www.electropedia.org

Le premier dictionnaire en ligne au monde de termes électroniques et électriques. Il contient plus de 20 000 termes et définitions en anglais et en français, ainsi que les termes équivalents dans les langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International en ligne.

- Service Clients: www.iec.ch/webstore/custserv/custserv_entry-f.htm

Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions, visitez le FAQ du Service clients ou contactez-nous:

Email: csc@iec.ch
Tél.: +41 22 919 02 11
Fax: +41 22 919 03 00

INTERNATIONAL STANDARD

NORME INTERNATIONALE

BASIC EMC PUBLICATION
PUBLICATION FONDAMENTALE EN CEM

AMENDMENT 2
AMENDEMENT 2

**Electromagnetic compatibility (EMC) –
Part 4-3: Testing and measurement techniques – Radiated, radio-frequency,
electromagnetic field immunity test**

**Compatibilité électromagnétique (CEM) –
Partie 4-3: Techniques d'essai et de mesure – Essai d'immunité aux champs
électromagnétiques rayonnés aux fréquences radioélectriques**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

PRICE CODE
CODE PRIX

F

ICS 33.100.20

ISBN 978-2-88910-373-7

FOREWORD

This amendment has been prepared by subcommittee 77B: High frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

The text of this amendment is based on the following documents:

FDIS	Report on voting
77B/626/FDIS	77B/629/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of this amendment and the base publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

CONTENTS

Add the title of Annex J as follows:

Annex J (informative) Measurement uncertainty due to test instrumentation

Add, after Annex I, the following new Annex J:

Annex J (informative)

Measurement uncertainty due to test instrumentation

J.1 General

This annex gives information related to measurement uncertainty (MU) of the test level setting according to the particular needs of the test method contained in the main body of the standard. Further information can be found in [1, 2]¹.

This annex shows an example of how an uncertainty budget can be prepared based upon level setting. Other parameters of the disturbance quantity such as modulation frequency and modulation depth, harmonics produced by the amplifier may also need to be considered in an appropriate way by the test laboratory. The methodology shown in this annex is considered to be applicable to all parameters of the disturbance quantity.

The uncertainty contribution for field homogeneity including test site effects is under consideration.

J.2 Uncertainty budgets for level setting

J.2.1 Definition of the measurand

The measurand is the hypothetical test electric field strength (without an EUT) at the point of the UFA selected according to the process of 6.2.1 step a) and 6.2.2 step a) of this standard.

J.2.2 MU contributors of the measurand

The following influence diagram (see Figure J.1) gives an **example** of influences upon level setting. It applies to both calibration and test processes and it should be understood that the diagram is not exhaustive. The most important contributors from the influence diagram have been selected for the uncertainty budget Tables J.1 and J.2. As a minimum, the contributions listed in Tables J.1 and J.2 shall be used for the calculation of the uncertainty budgets in order to get comparable budgets for different test sites or laboratories. It is noted that a laboratory may include additional contributors in the calculation of the MU, on the basis of its particular circumstances.

¹ Figures in square brackets refer to the reference documents in Clause J.4.